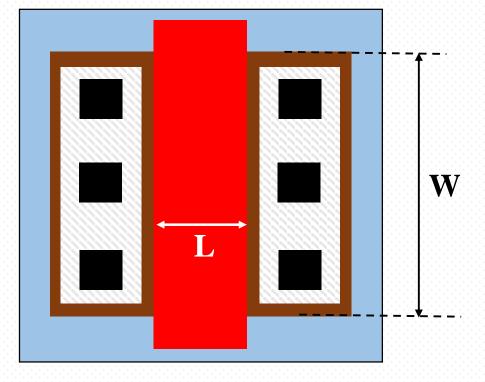
Metal-Oxide-Semiconductor FIELD EFFECT TRANSISTOR

Santunu Sarangi

Metal-Oxide-Semiconductor Field Effect Transistor (MOSFET)

Top View (Layout View) of MOSFET



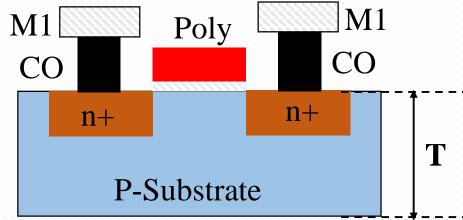
Layout Layers:

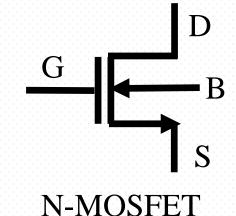
- P-substrate
- Thin oxide
- Polysilicon
- n+ diffusion
- Contact
- Metal

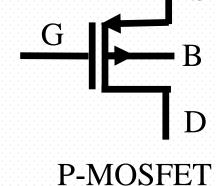
Layout Rules:

- Min. width
- Max Width
- Spacing
- Area
- Enclosure
- Extension

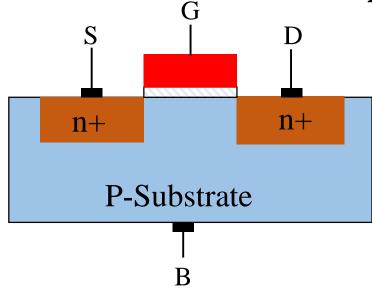
Front View (Cross-section) of MOSFET

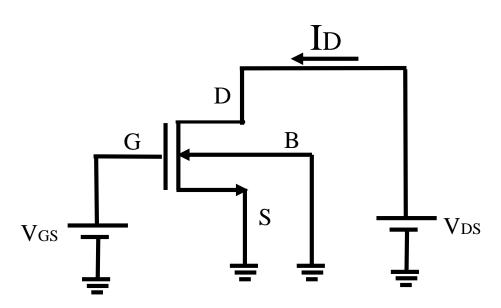






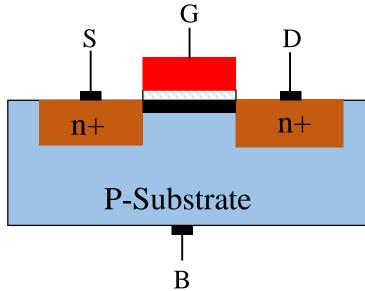
MOSFET Operation (N-Channel Enhancement)

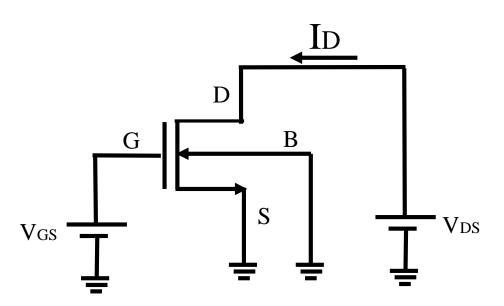




- Case-1: $V_{GS} < V_T$
 - Cutoff
- Case-2: $V_{GS} > V_T$
 - Linear or Saturation
 - Linear: $V_{GS} V_T > V_{DS}$
 - Saturation: $V_{GS} V_T \le V_{DS}$
- $I_{D-Cutoff} = 0$
- $I_{D-Lin.} = \mu_n C_{ox} \frac{W}{L} \left\{ (V_{GS} V_T) V_{DS} \frac{VDS^2}{2} \right\}$
- $I_{D-Sat.} = \mu_n C_{ox} \frac{W}{2L} \{ (V_{GS} V_T)^2 (1 + \lambda V_{DS}) \}$

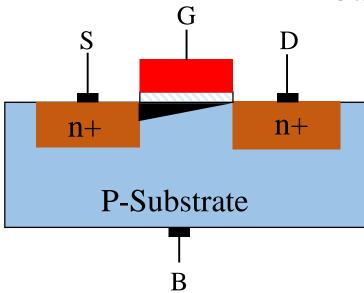
MOSFET Operation: Linear

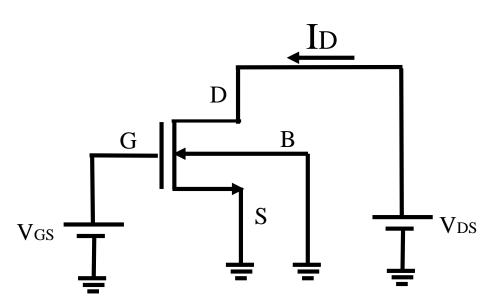




- Case-1: $V_{GS} < V_T$
 - Cutoff
- Case-2: $V_{GS} > V_T$
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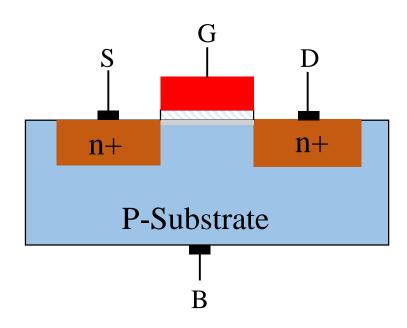
MOSFET Operation: Saturation





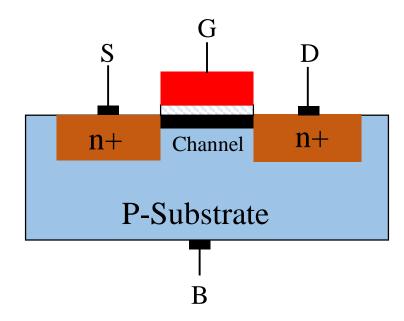
- Case-1: $V_{GS} < V_T$
 - Cutoff
- Case-2: $V_{GS} > V_T$
 - Linear or Saturation
 - Linear: $V_{GS} V_T > V_{DS}$
 - Saturation: $V_{GS} V_T \le V_{DS}$
- $I_{D-Cutoff} = 0$
- $I_{D-Lin.} = \mu_n C_{ox} \frac{W}{L} \left\{ (V_{GS} V_T) V_{DS} \frac{VDS^2}{2} \right\}$
- $I_{D-Sat.} = \mu_n C_{ox} \frac{W}{2L} \{ (V_{GS} V_T)^2 (1 + \lambda V_{DS}) \}$

MOSFET Channel Profile



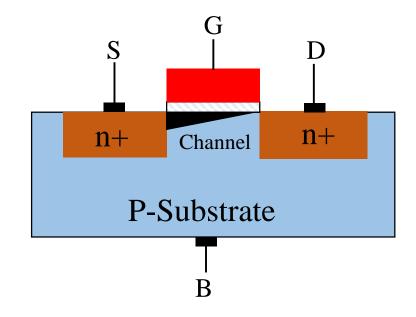
MOSFET in cutoff mode of operation

• Application: Switch



MOSFET in linear or triode mode of operation

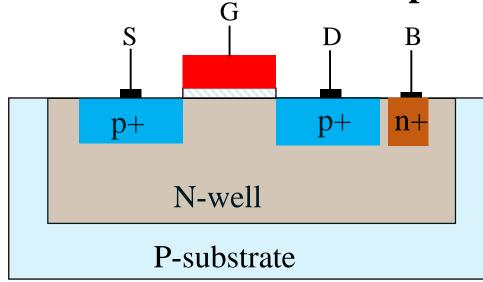
• Application: switch and linear resistor

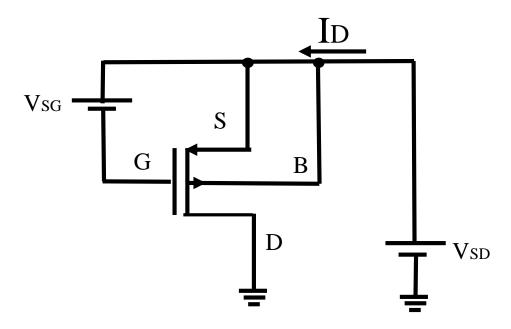


MOSFET in saturation mode of operation

 Application: Amplifier and constant current source

MOSFET Operation (P-Channel Enhancement)



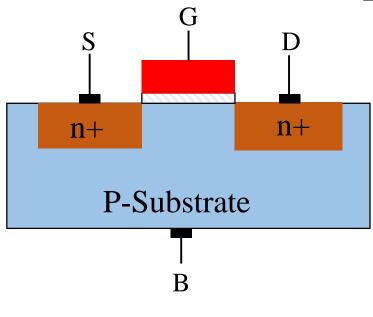


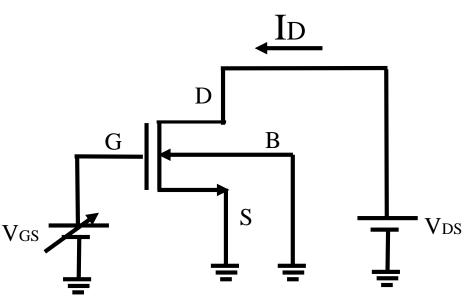
- Case-1: $V_{SG} < |V_T|$
 - Cutoff
- Case-2: $V_{SG} > |V_T|$
 - Linear or Saturation
 - Linear: $V_{SG} |V_{T}| > V_{SD}$
 - Saturation: $V_{SG} |V_T| \le V_{SD}$
- $I_{D-Cutoff} = 0$

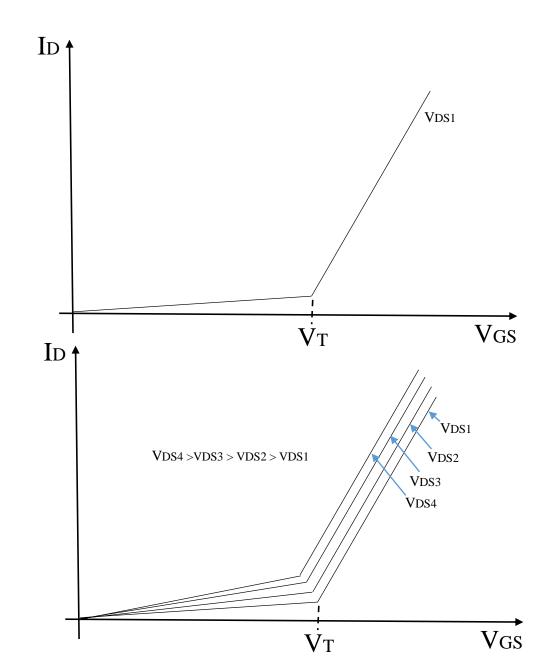
•
$$I_{D-Lin.} = \mu_p C_{ox} \frac{W}{L} \left\{ (V_{SG} - |V_T|) V_{DS} - \frac{VDS^2}{2} \right\}$$

•
$$I_{D-Sat.} = \mu_p C_{ox} \frac{W}{2L} \{ (V_{SG} - |V_T|)^2 (1 + \lambda V_{SD}) \}$$

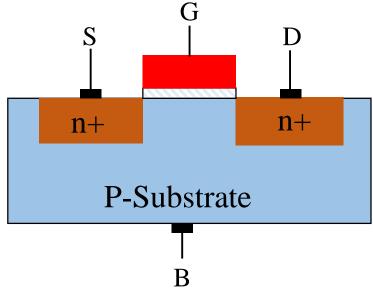
ID-VGS Characteristics

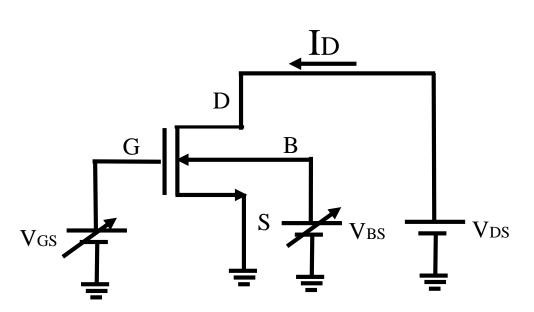


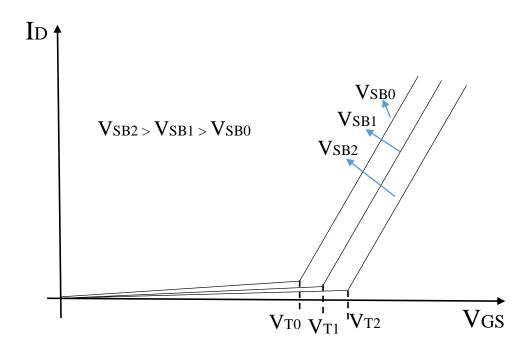




ID-VGS Characteristics with Body Bias





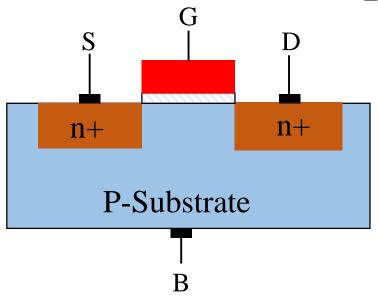


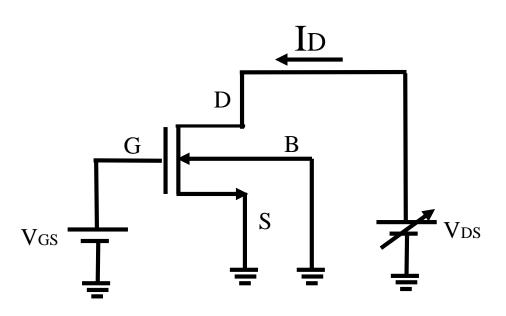
$$V_{T} = V_{T0} + \left\{ \sqrt{2\phi_f + V_{SB}} - \sqrt{2\phi_f} \right\}$$

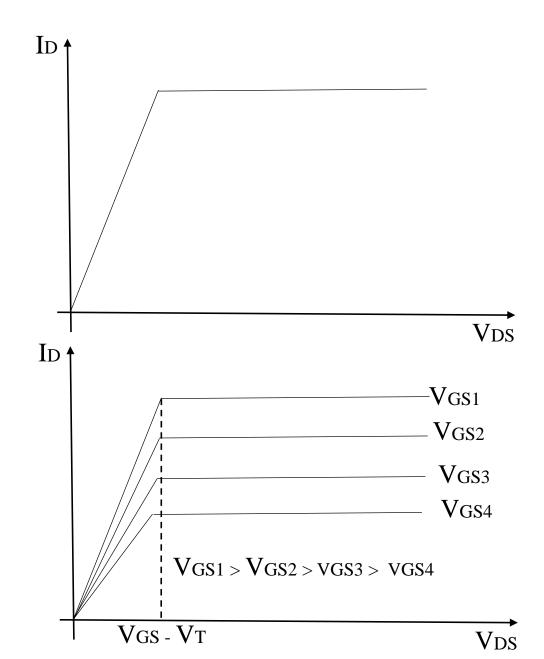
$$V_{T0} = \left\{ \frac{\sqrt{q\varepsilon_{si}N_A\phi_t}}{C_{ox}} + \phi_t \right\}$$

$$\phi_t = 2\phi_f \qquad \phi_f = \frac{kT}{q} \ln \frac{N_A}{n_i}$$

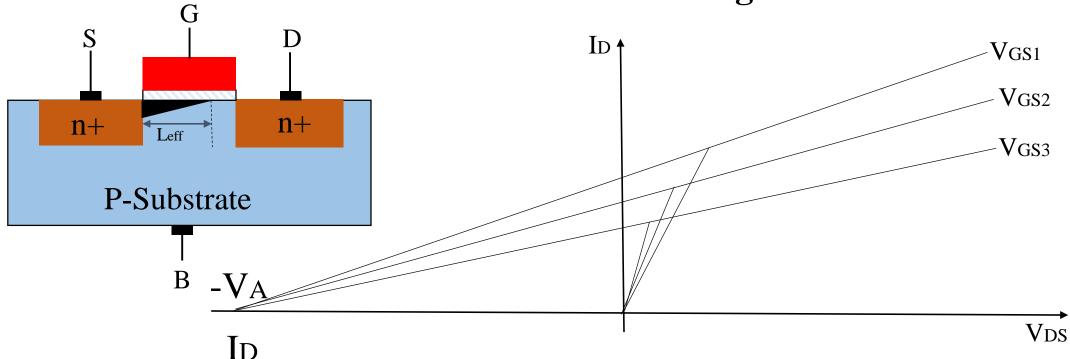
ID-VDS Characteristics

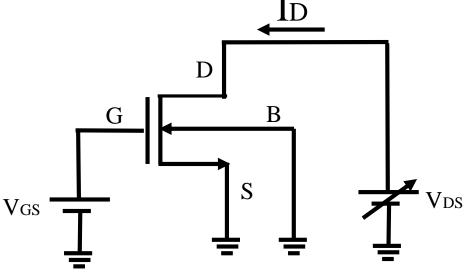






ID-VDS Characteristics: Channel Length Modulation





$$I_{D-Sat.} = \mu_p C_{ox} \frac{W}{2L} \{ (V_{SG} - |V_T|)^2 (1 + \lambda V_{SD}) \}$$

 $V_{A} = \text{Early voltage} \\ \lambda = \text{Channel length modulation parameter}$

$$\lambda = \frac{1}{V_A}$$

Thank You